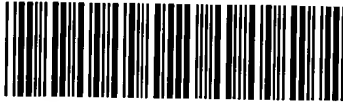


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/943,690	WEIER ET AL.	
	Examiner	Art Unit	
	Tae H. Yoon	1714	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
524		504		524	819	823			
INTERNATIONAL CLASSIFICATION?				523	201	206			
C08L	5100	525	71						
C08L	33100								
	/								
	/								
	/								
(Assistant Examiner) (Date)				TAE H. YOON PRIMARY EXAMINER				Total Claims Allowed: 8	
(Legal Instruments Examiner) (Date)				Tae H. Yoon 11-13-04 (Primary Examiner) (Date)				O.G. Print Claim(s) 1	O.G. Print Fig. —

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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